Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	1	(repairing adj3 group adj2 elements)	US-PGPUB	OR	OFF	2005/10/19 15:41
L3	4	(repairing adj5 elements) and inhibiting	US-PGPUB	OR	OFF	2005/10/19 15:41

Ex initial EA

DB = east

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L14	736	(test$3 near5 (memory or element$1 or components or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$4 near5 (error$1 or fault$1 or defect$1)) and (repair$4 or replac45) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:57
L15	488	((test$3 near5 (memory or element$1 or components or unit$1 or IC$1 or device$1 or circuit$1)) same (detect$4 near5 (error$1 or fault$1 or defect$1))) and (repair$4 or replac$5) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:55
L16	364	((test$3 adj4 (memory or memories or element$1 or components or unit$1 or IC$1 or device$1 or circuit$1)) same (detect$5 near5 (error$1 or fault$1 or defect$1))) and (repair$4 or replac$5) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:55
L17	73	((test$3 near5 (memory or element$1 or components or unit$1 or IC$1 or device$1 or circuit$1)) same (detect$4 near5 (error$1 or fault$1 or defect$1)) same (repair$4 or replac$5)) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:55
L18	190	(test$3 adj4 (memory or memories or element$1 or component$1 or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$5 near5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) same inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:55
L19	153	(test$3 adj4 (memory or memories or element$1 or component$1 or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) same inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:59
L20	41	(test$3 adj4 (memory or memories or element$1 or component$1 or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) near15 inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:56

L21	33	(test$3 adj4 (memory or memories or element$1 or component$1 or unit$1 or IC$1 or device$1 or circuit$1)) and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) near10 inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 14:56
L22	438	test$3 and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and ((repair$4 or replac$5) near5 (element$1 or component$1)) and inhibit$4	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 15:01
L23	16	test$3 and (detect$5 adj5 (error$1 or fault$1 or defect$1)) and (((repair$4 or replac$5) near5 (element$1 or component$1)) same inhibit$4)	USPAT; EPO; JPO; DERWENT	OR	OFF	2005/10/19 15:01

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Kuen-Jong Lee; Jih-Jeen Chen; Cheng-Hua Huang;
Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction
Volume 18, Issue 12, Dec. 1999 Page(s):1793 - 1802
Digital Object Identifier 10.1109/43.811328
AbstractPlus | References | Full Text: PDF(300 KB) **IEEE JNL**

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Stroud, C.E.;
Design & Test of Computers, IEEE
Volume 5, Issue 6, Dec. 1988 Page(s):22 - 32
Digital Object Identifier 10.1109/54.9269
AbstractPlus | Full Text: PDF(724 KB) **IEEE JNL**

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Koren, I.; Koren, Y.; Oomman, B.G.;
Computer Arithmetic, 2003. Proceedings. 16th IEEE Symposium on
15-18 June 2003 Page(s):228 - 235
Digital Object Identifier 10.1109/ARITH.2003.1207683
AbstractPlus | Full Text: PDF(335 KB) **IEEE CNF**

☐ **4. An approach for evaluation of redundancy analysis algorithms**
Shoukourian, S.; Vardanian, V.; Zorian, Y.;
Memory Technology, Design and Testing, IEEE International Workshop on, 20
6-7 Aug. 2001 Page(s):51 - 55
Digital Object Identifier 10.1109/MTDT.2001.945228
AbstractPlus | Full Text: PDF(300 KB) **IEEE CNF**

☐ **5. The exponential distribution: the good, the bad and the ugly. A practical g implementation**
Murphy, K.E.; Carter, C.M.; Brown, S.O.;
Reliability and Maintainability Symposium, 2002. Proceedings. Annual
28-31 Jan. 2002 Page(s):550 - 555
Digital Object Identifier 10.1109/RAMS.2002.981701
AbstractPlus | Full Text: PDF(506 KB) **IEEE CNF**

☐ **6. Fault tolerant techniques for memory components**

Kubo, M.; Sunlin Chou;
Solid-State Circuits Conference. Digest of Technical Papers. 1985 IEEE Intern
Volume XXVIII, Feb 1985 Page(s):230 - 231

AbstractPlus | Full Text: PDF(352 KB) **IEEE CNF**

☐ **7. Optimal reconfiguration functions for column or data-bit built-in self-repa**
Nicolaidis, M.; Achouri, N.; Boutobza, S.;
Design, Automation and Test in Europe Conference and Exhibition, 2003
2003 Page(s):590 - 595
Digital Object Identifier 10.1109/DATE.2003.1253672

AbstractPlus | Full Text: PDF(263 KB) **IEEE CNF**

☐ **8. Viterbi decoder architecture for interleaved convolutional code**
Jun Jin Kong; Parhi, K.K.;
Signals, Systems and Computers, 2002. Conference Record of the Thirty-Sixth
Conference on
Volume 2, 3-6 Nov. 2002 Page(s):1934 - 1937 vol.2

AbstractPlus | Full Text: PDF(326 KB) **IEEE CNF**

☐ **9. Built in self repair for embedded high density SRAM**
Ilyoung Kim; Zorian, Y.; Komoriya, G.; Pham, H.; Higgins, F.P.; Lewandowski,
Test Conference, 1998. Proceedings. International
18-23 Oct. 1998 Page(s):1112 - 1119
Digital Object Identifier 10.1109/TEST.1998.743312

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